

10/549991

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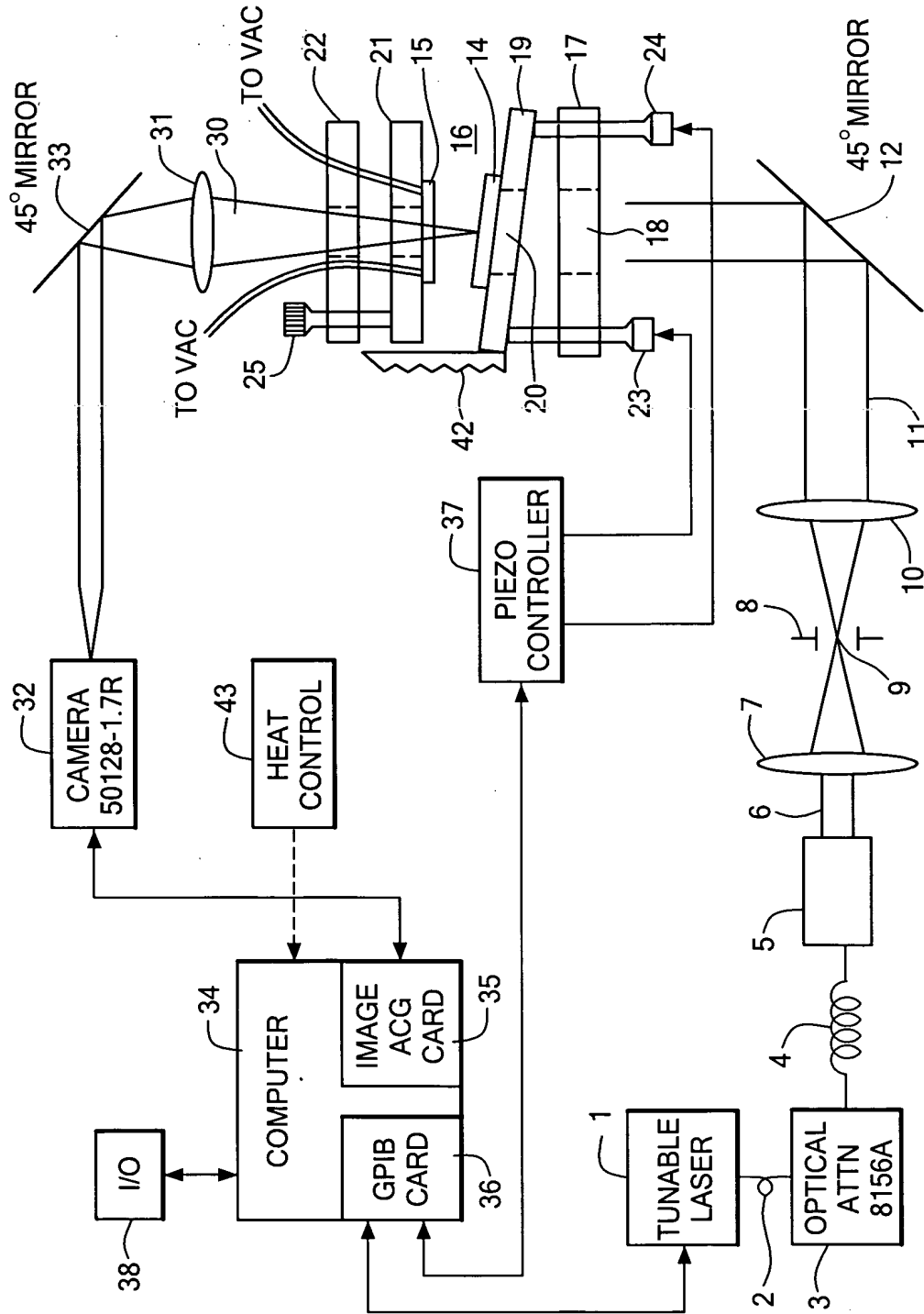


FIG. 1

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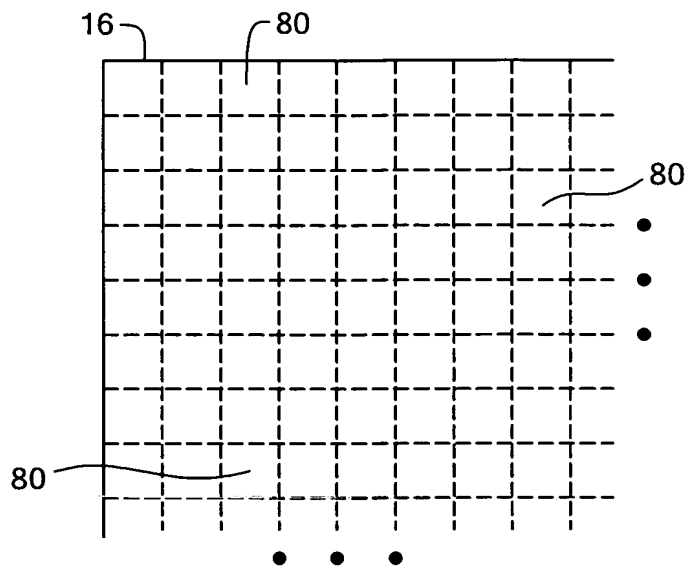


FIG. 2

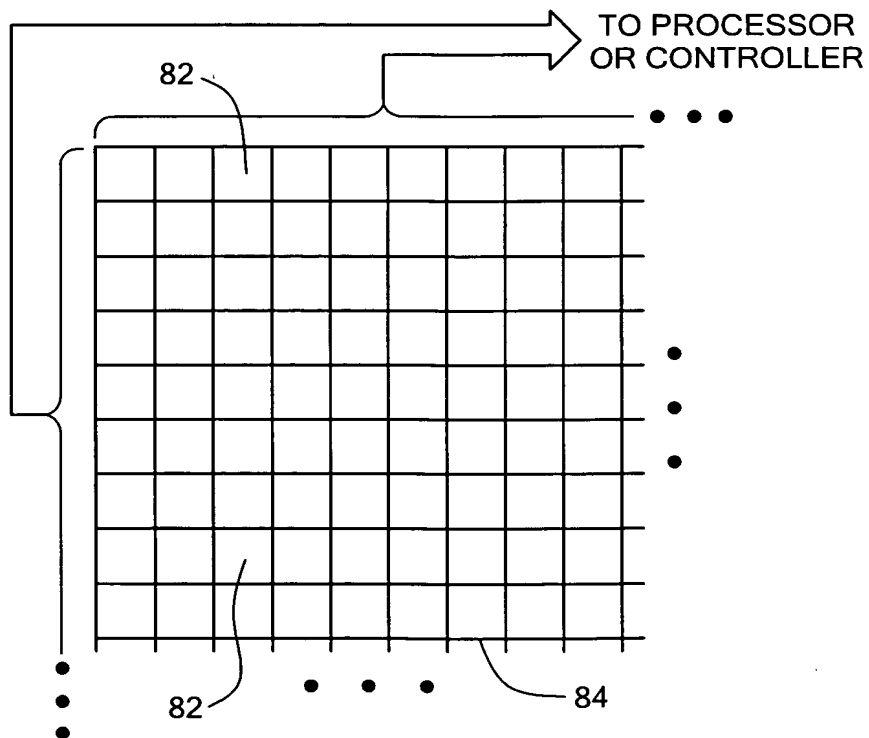
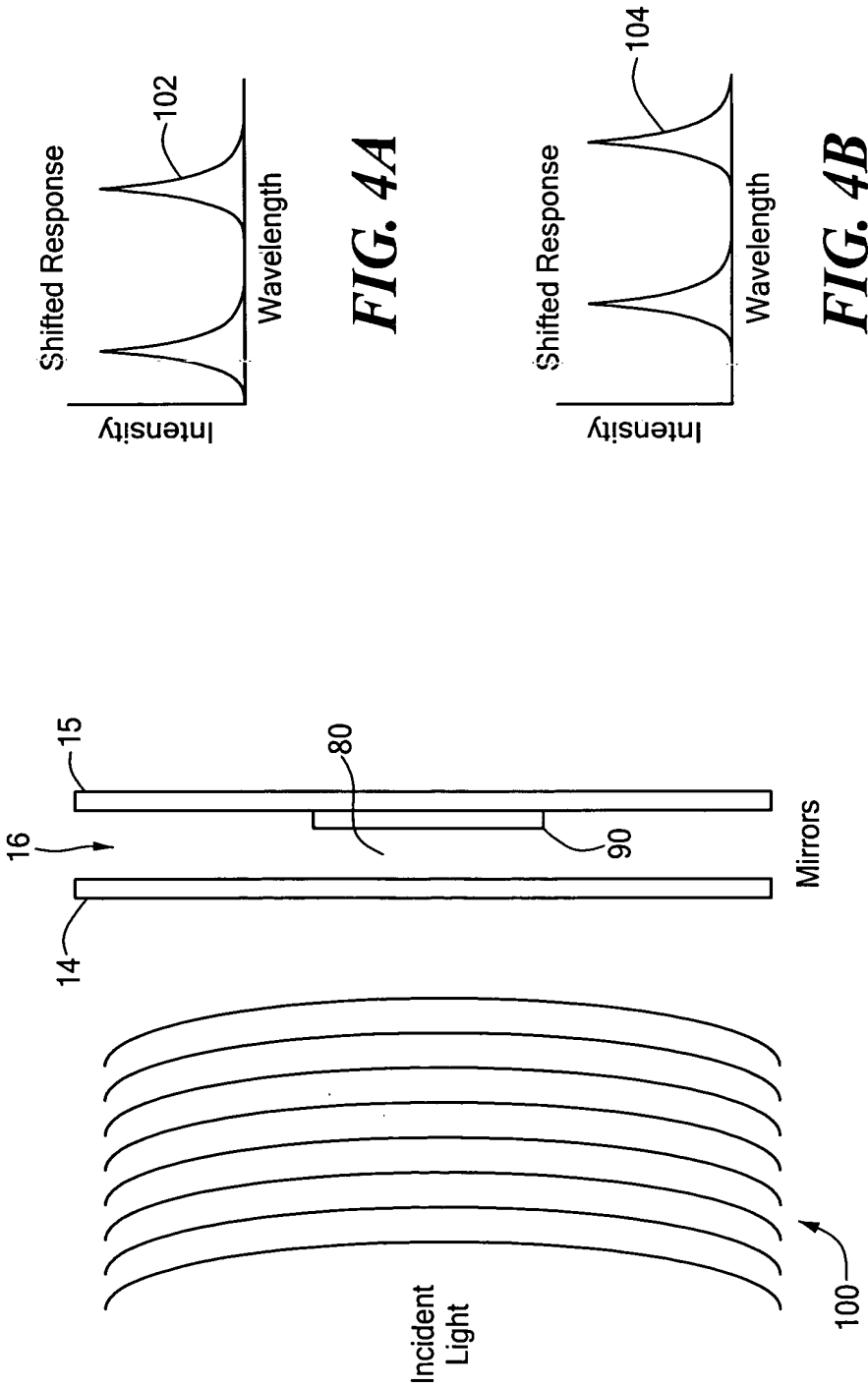


FIG. 3



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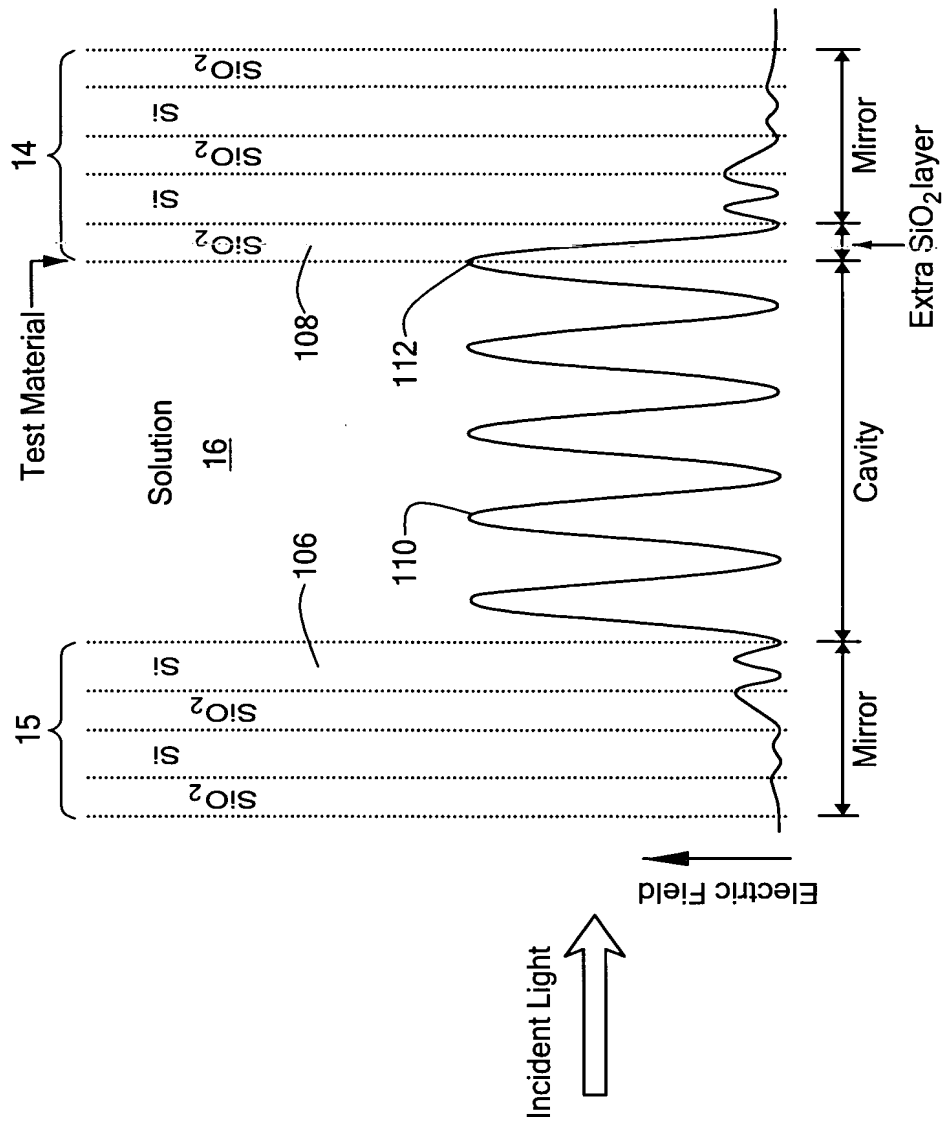


FIG. 5

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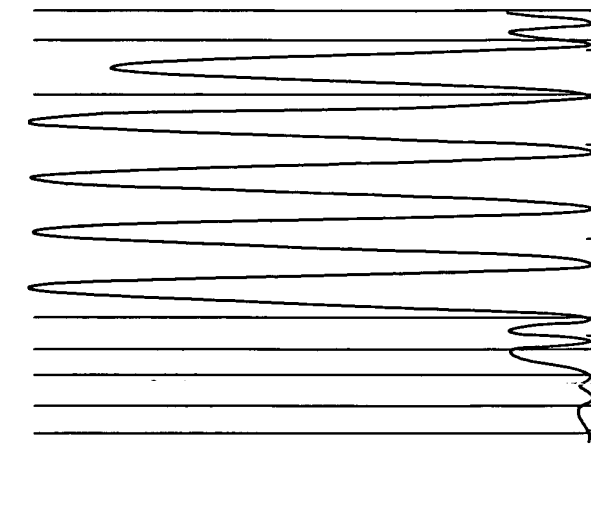


FIG. 6B

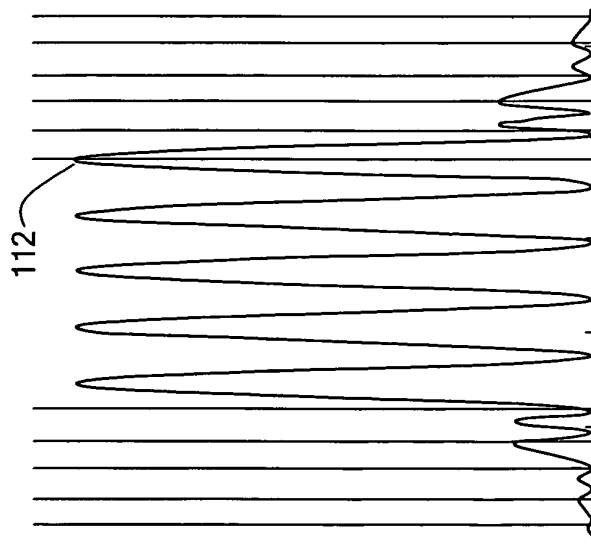


FIG. 6A

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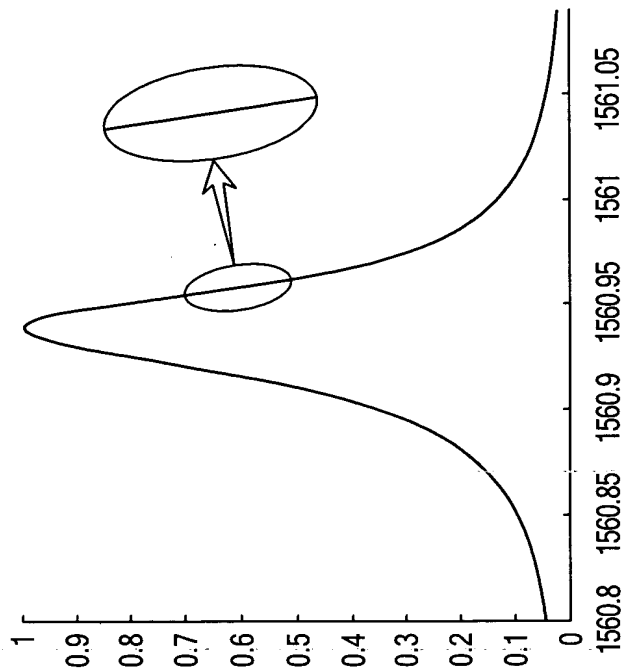


FIG. 7B

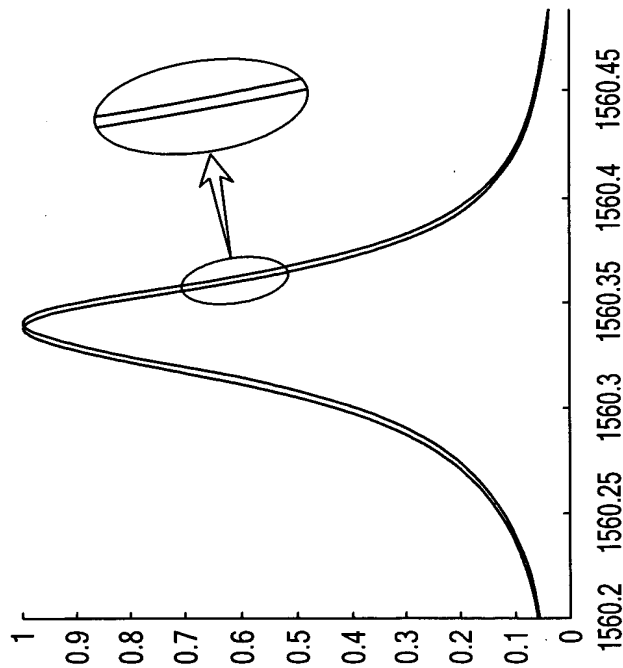


FIG. 7A

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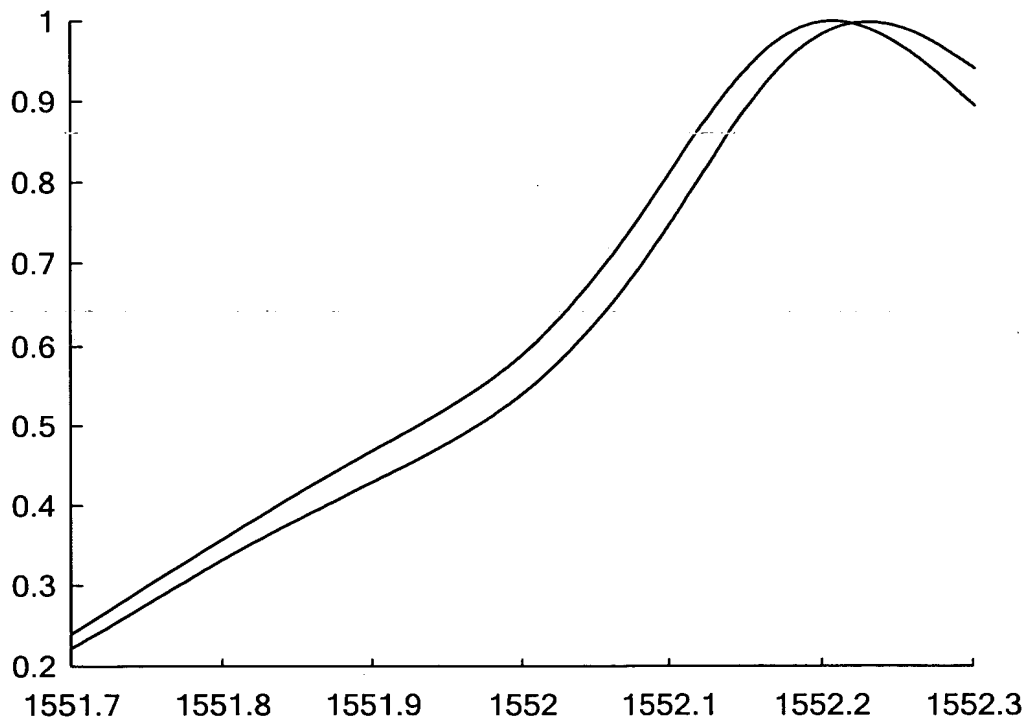


FIG. 8A

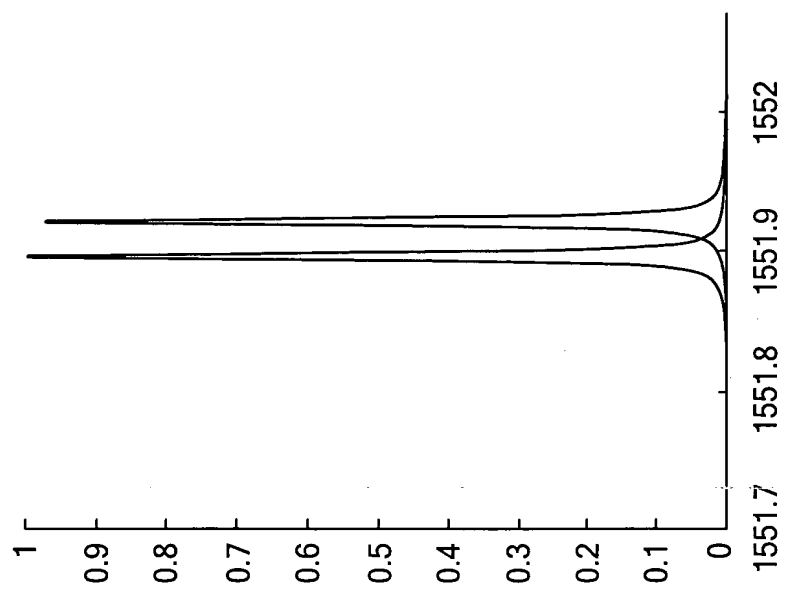


FIG. 8C

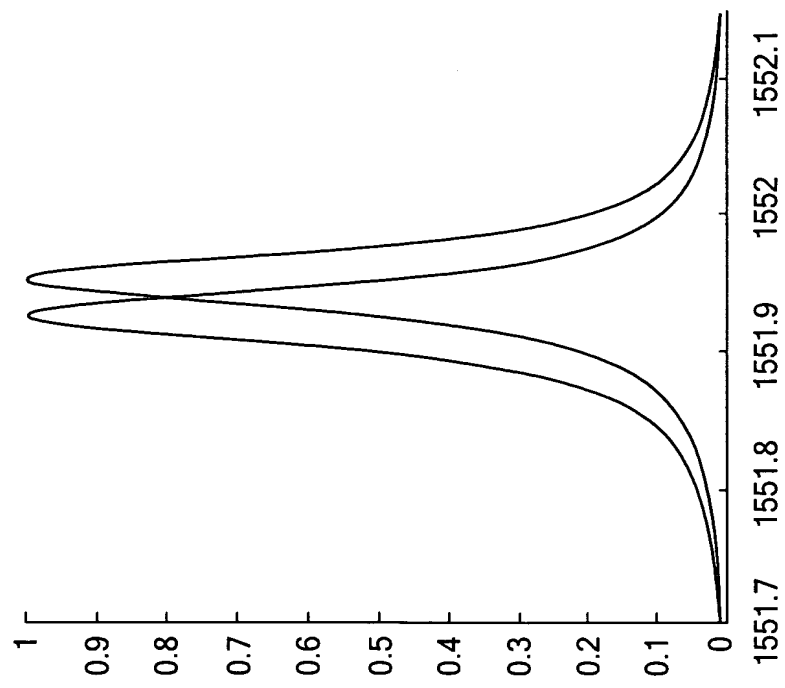


FIG. 8B

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FIG. 9A

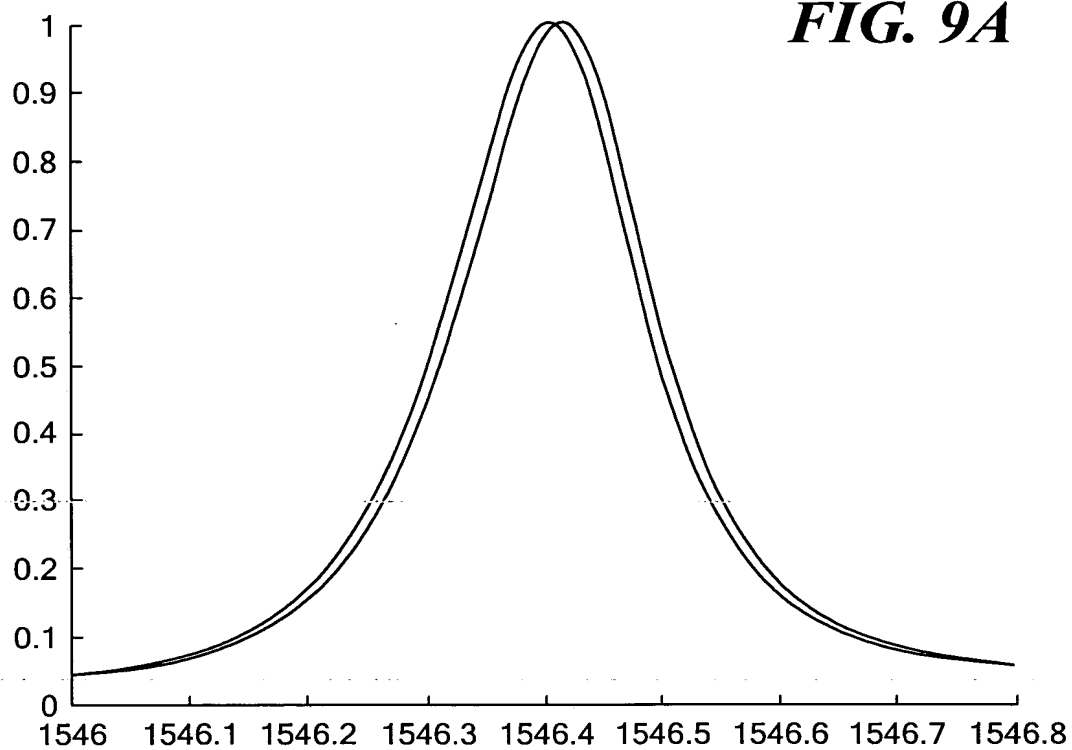
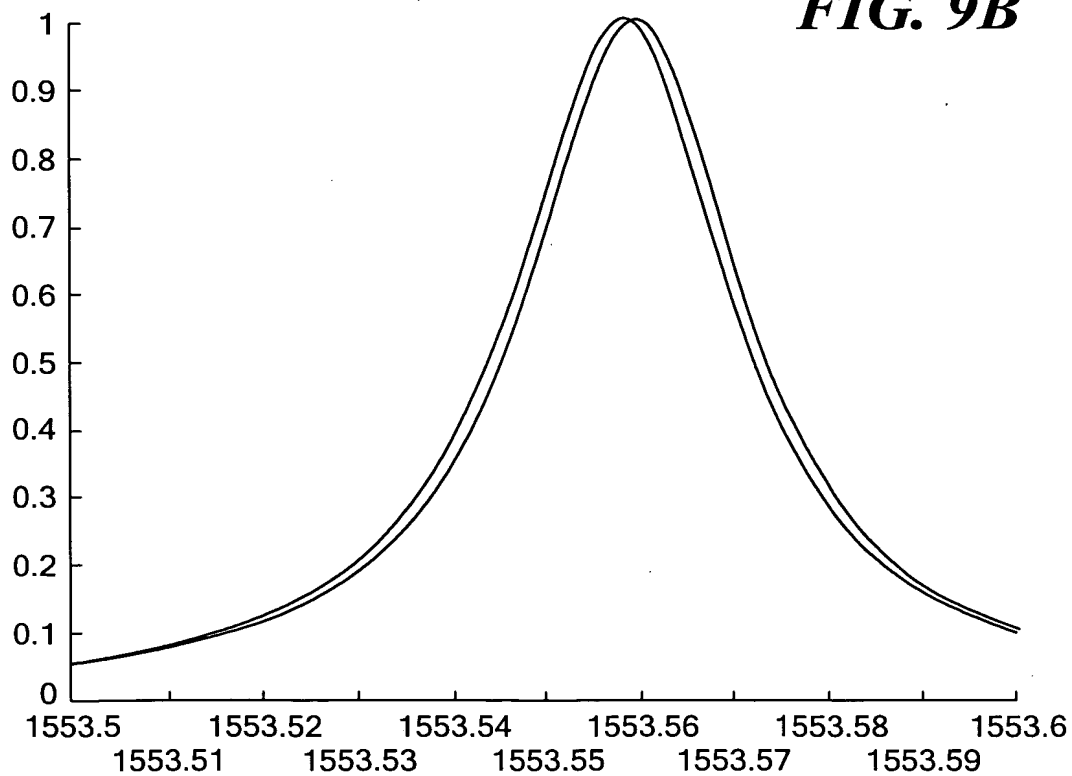


FIG. 9B



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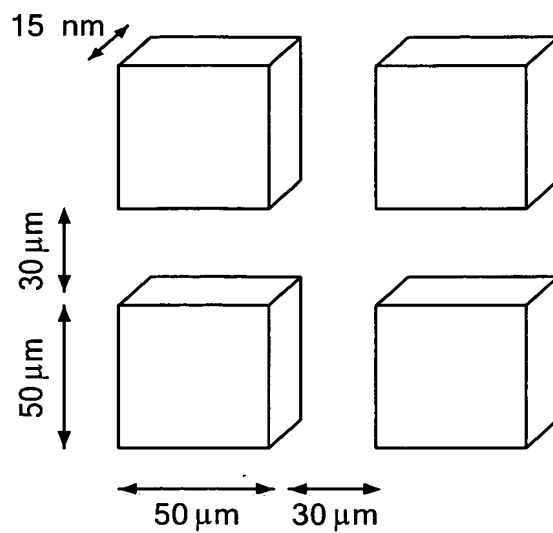


FIG. 10A

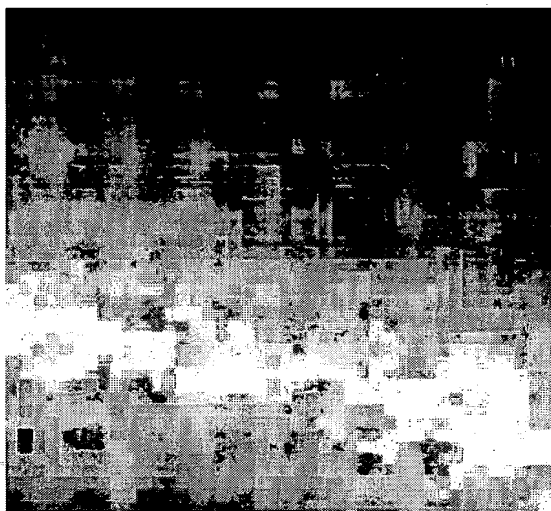


FIG. 10B



FIG. 10C

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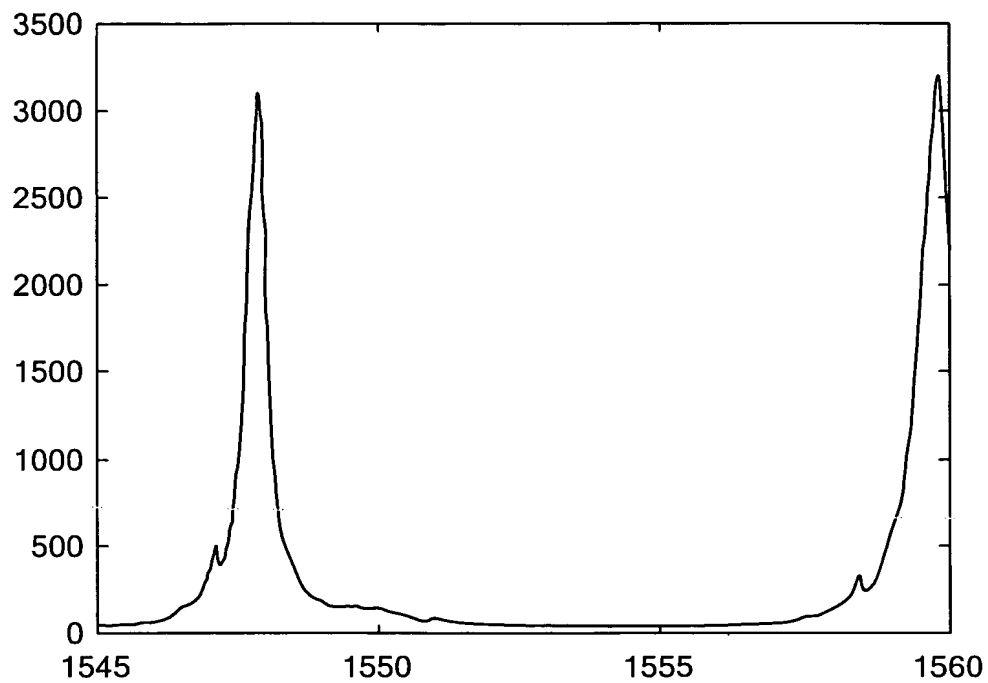


FIG. 10D

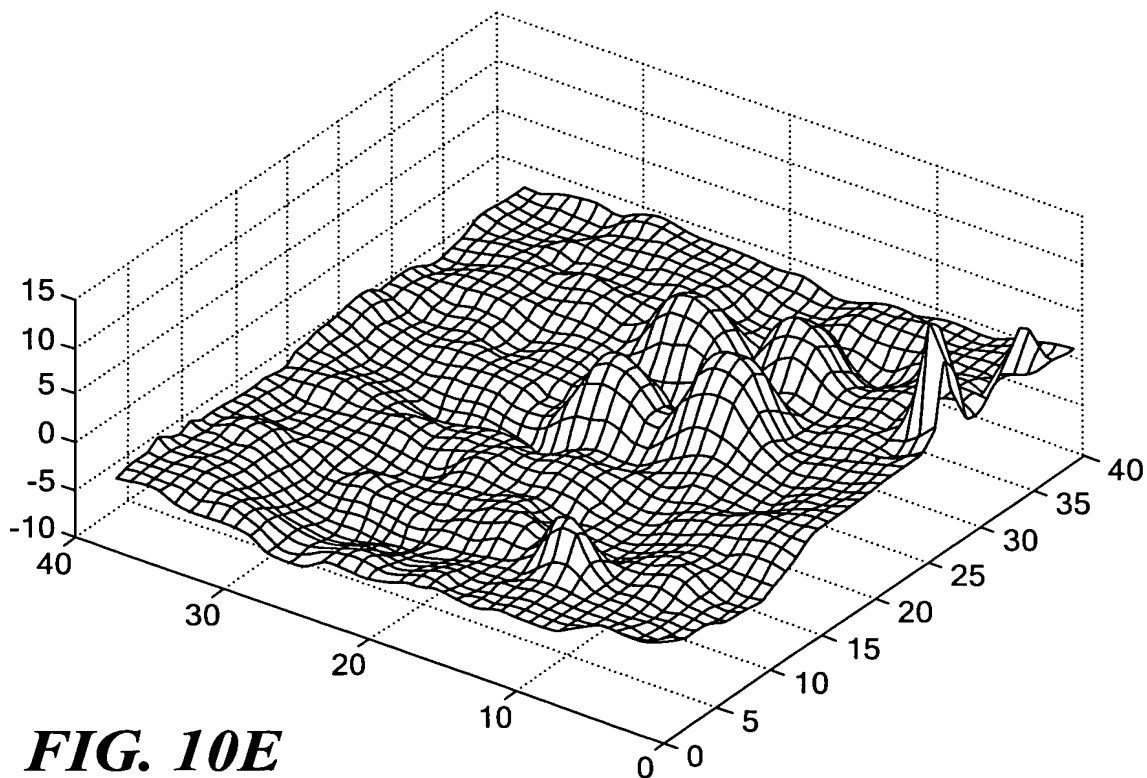


FIG. 10E

Figure 1 shows two cross-sectional views of a substrate. The top view shows a substrate 140 with a thin film 142. The thin film 142 has a top layer 142' and a bottom layer 142. The thin film 142 is on a substrate 144. The bottom layer 142 has a patterned layer 146. The bottom view shows a substrate 150 with a thin film 152. The thin film 152 has a top layer 158 and a bottom layer 150. The thin film 152 is on a substrate 148. The bottom layer 150 has a patterned layer 156. The bottom layer 150 has a patterned layer 156. The bottom layer 150 has a patterned layer 156.

The diagram illustrates a detection system 168 positioned above a multi-layered structure 162. The structure 162 consists of a top layer 164 and a bottom layer 166. A detection system 168 is shown above the structure 162, with four upward-pointing arrows indicating the direction of detection or measurement. Below the structure 162, there are three additional multi-layered structures 148, each with a top layer 148 and a bottom layer 160. Arrows 160 point upwards from the bottom layer 160 of these structures towards the structure 162. The entire assembly is shown on a horizontal base.

FIG. 12